

1	<b>MEASUREMENT SYSTEM IN A SPECIFIC ENVIRONMENT</b>	39	...Sound energy (e.g., ultrasonic)
2	.Earth science	40	...Radiant energy (e.g., X-ray, infrared, laser)
3	..Weather	41	..Force or torque measurement
4	...Lightning	42	...Stress or strain measurement
5	..Topography (e.g., land mapping)	43	....Torsional, shear, tensile, or compression
6	..Well logging or borehole study	44	...Mechanical work or power measurement
7	...By induction or resistivity logging tool	45	..Flow metering
8	...By radiation (e.g., nuclear, gamma, X-ray)	46	...Count or pulse
9	...Drilling	47	...Pressure, resistive, or capacitive sensor
10	...Dipmeter	48	...Acoustic
11	...Formation characteristic	49	...Radiant energy
12	....Fluid flow investigation	50	..Fluid measurement (e.g., mass, pressure, viscosity)
13	....Hydrocarbon prospecting	51	...Leak detecting
14	..Seismology	52	...Capacitive sensor
15	...Earthquake or volcanic activity	53	...Resistive sensor
16	...Specific display system (e.g., mapping, profiling)	54	...Acoustic or vibration sensor
17	...Filtering or noise reduction/removal	55	...Liquid level or volume determination
18	...Velocity of seismic wave	56	..Vibration detection
19	..Biological or biochemical	57	..Electrical signal parameter measurement system
20	..Gene sequence determination	58	..For electrical fault detection
21	..Cell count or shape or size analysis (e.g., blood cell)	59	...Fault location
22	..Chemical analysis	60	..Power parameter
23	..Quantitative determination (e.g., mass, concentration, density)	61	...Power logging (e.g., metering)
24	..Gaseous mixture (e.g., solid-gas, liquid-gas, gas-gas)	62	....Including communication means
25	..Liquid mixture (e.g., solid-liquid, liquid-liquid)	63	...Battery monitoring
26	..By particle count	64	..Voltage or current
27	..Molecular structure or composition determination	65	...Including related electrical parameter
28	...Using radiant energy	66	..Waveform analysis
29	..Particle size determination	67	...Display of waveform
30	..Chemical property analysis	68	....Having specified user interface (e.g., marker, menu)
31	..Specific operation control system	69	...Signal quality (e.g., timing jitter, distortion, signal-to-noise ratio)
32	..Specific signal data processing	70	...Waveform extraction
33	..Mechanical measurement system	71	...Waveform-to-waveform comparison
34	..Wear or deterioration evaluation	72	....Phase comparison
35	..Flaw or defect detection	73	....Identification of waveform
36	...Location	74	....Signal-in-signal determination
38	...Electromagnetic (e.g., eddy current)	75	...Frequency
		76	....Frequency spectrum
		77	....Using Fourier method

78	....By count (e.g., pulse)	118	..Testing multiple circuits
79	..Time-related parameter (e.g., pulse-width, period, delay, etc.)	119	..Including program initialization (e.g., program loading) or code selection (e.g., program creation)
80	..Specified memory location generation for storage	120	..Including input/output or test mode selection means
81	.Quality evaluation		
82	..Having judging means (e.g., accept/reject)	121	..Including multiple test instruments
83	..Sampling Inspection Plan	122	..Including specific communication means
84	..Quality control		
85	<b>CALIBRATION OR CORRECTION SYSTEM</b>	123	..Including program set up
86	.Linearization of measurement	124	..Signal generation or waveform shaping
87	.Zeroing (e.g., null)		
88	.Zero-full scaling	125	..Timing signal
89	.Timing (e.g., delay, synchronization)	126	..Signal conversion
90	.Error due to component compatibility	127	<b>MEASUREMENT SYSTEM</b>
91	..Having interchangeable sensors or probes	128	.Article count or size distribution
92	.Direction (e.g., compass)	129	..Quantitative determination by weight
93	..By another sensor	130	.Temperature measuring system
94	.Position measurement	131	..Body temperature
95	..Coordinate positioning	132	..Thermal protection
96	.Speed	133	..By resistive means
97	.Length, distance, or thickness	134	..By radiant energy
98	.Pressure	135	...Infrared
99	.Temperature	136	..Thermal related property
100	.Fluid or fluid flow measurement	137	.Density
101	.Weight	138	.Pressure
102	..Tare weight adjusted	139	..Exerted on or by a living body
103	.Acoustic	140	..Within an enclosure
104	.Sensor or transducer	141	.Accelerometer
105	.For mechanical system	142	.Speed
106	.Signal frequency or phase correction	143	..By radar or sonar
107	.Circuit tuning (e.g., potentiometer, amplifier)	144	..Of aircraft
108	<b>TESTING SYSTEM</b>	145	..Rotational speed
109	.For transfer function determination	146	...Averaging performed
110	..Binary signal stimulus (e.g., pulse)	147	...Specific mathematical operation performed
111	..Noise signal stimulus (e.g., white noise)	148	....For wheel speed
112	..Sinusoidal signal stimulus	149	..By distance and time measurement
113	.Of mechanical system	150	.Orientation or position
114	..Pneumatic or hydraulic system	151	..Angular position
115	..Electromechanical or magnetic system	152	..3D position
116	.Of sensing device	153	...3D orientation
117	.Of circuit	154	..Inclinometer
		155	.Dimensional determination
		156	..Area or volume
		157	..Radius or diameter
		158	..Linear distance or length

159 ...By reflected signal (e.g.,  
ultrasonic, light, laser)

160 ...Pedometer

161 ...Electronic ruler

162 ...Micrometer

163 ...By rotary encoding means

164 ....Electronic tape measure

165 ....Odometer

166 ..Height or depth

167 ..Contouring

168 ...By probe (e.g., contact)

169 ...Center of gravity

170 ..Thickness or width

171 ...By ultrasonic

172 ...By radiant energy (e.g., X-  
ray, light)

173 ..Weight

174 ..Payload

175 ..Of moving article

176 ..Time duration or rate

177 ..Due time monitoring (e.g.,  
medication clock, maintenance  
interval)

178 ..Timekeeping (e.g., clock,  
calendar, stopwatch)

179 ..Statistical measurement

180 ..Histogram distribution

181 ..Probability determination

182 ..Performance or efficiency  
evaluation

183 ..Diagnostic analysis

184 ...Maintenance

185 ...Cause or fault identification

186 ..Computer and peripheral  
benchmarking

187 ..History logging or time stamping

188 ..Remote supervisory monitoring

189 ..Measured signal processing

190 ..Signal extraction or separation  
(e.g., filtering)

191 ...For noise removal or  
suppression

193 ....By threshold comparison

194 ....By mathematical attenuation  
(e.g., weighting, averaging)

195 .....Subtracting noise component

196 ..Using matrix operation

197 ....Having multiple filtering  
stages

198 ..Measurement conversion  
processing (e.g., true-to-RMS  
value)

199 ..Averaging

**FOREIGN ART COLLECTIONS****FOR 000 CLASS-RELATED FOREIGN DOCUMENTS**

Any foreign patents or non-patent literature from subclasses that have been reclassified have been transferred directly to FOR Collections listed below. These Collections contain ONLY foreign patents or non-patent literature. The parenthetical references in the Collection titles refer to the abolished subclasses from which these Collections were derived.

**APPLICATIONS (364/400)**

FOR 100 ..Earth sciences (e.g., weather)  
(364/420)

FOR 101 ..Seismology (364/421)

FOR 102 ..Well logging (364/422)

FOR 103 ..Electrical/electronic  
engineering (364/480)

FOR 104 ..Measuring or testing (364/481)

FOR 105 ...Impedance (364/482)

FOR 106 ...Voltage, current, or power  
(364/483)

FOR 107 ...Frequency (364/484)

FOR 108 ....Frequency spectrum (364/485)

FOR 109 ...Pulse (364/486)

FOR 110 ...Waveform (364/487)  
..Electrical/electronic  
engineering (364/480)

FOR 111 ..Power generation or  
distribution (364/492)

FOR 112 ...Economic dispatching (364/493)

FOR 113 ...Turbine or generator control  
(364/494)

FOR 114 ...With model (364/495)

FOR 115 ..Chemical and engineering  
sciences (364/496)

FOR 116 ..Chemical analysis (364/497)

FOR 117 ...Spectrum analysis  
(composition) (364/498)

FOR 118 ...Chemical property (364/499)

FOR 119 ..Chemical process control (364/  
500)

FOR 120 ...Distillation (364/501)

FOR 121 ...Physical mixing or separation  
(364/502)

FOR 122 ...Kilns (364/503)

- FOR 123 ..Mechanical and civil engineering (364/505)
- FOR 124 ...Measuring or testing (364/506)
- FOR 125 ....Flaw or defect (364/507)
- FOR 126 ....Stress, strain, or vibration (364/508)
- FOR 127 ....Fluid (364/509)
- FOR 128 ....Fluid flow (364/510)
- FOR 129 ....Power (364/511)
- FOR 130 ..Physics (364/524)
- FOR 131 ..Optics or photography (364/525)
- FOR 132 ...Color analysis (364/526)
- FOR 133 ..Atomic or nuclear physics (364/527)
- FOR 134 **MEASURING, TESTING, OR MONITORING (364/550)**
- FOR 135 ..Measuring and evaluating (e.g., performance) (364/551.01)
- FOR 136 ..Of machine tool (364/551.02)
- FOR 137 ..Quality control determinations (364/552)
- FOR 138 ..Transfer function evaluation (364/553)
- FOR 139 ..Statistical data (e.g., stochastic variable) (364/554)
- FOR 140 ..Particle count, distribution, size (364/555)
- FOR 141 ..For basic measurements (364/556)
- FOR 142 ..Temperature (364/557)
- FOR 143 ..Pressure or density (364/558)
- FOR 144 ..Orientation (364/559)
- FOR 145 ..Dimension (364/560)
- FOR 146 ...Distance (364/561)
- FOR 147 ....Length or height (364/562)
- FOR 148 ....Width or thickness (364/563)
- FOR 149 ...Area or volume (364/564)
- FOR 150 ..Rate of change of dimension (e.g., speed) (364/565)
- FOR 151 ..Acceleration and further derivatives (364/566)
- FOR 152 ..Weight (364/567)
- FOR 153 ...Basis weight (364/568)
- FOR 154 ..Time or time intervals (364/569)
- FOR 155 ..Operations performed (364/570)
- FOR 156 ..Calibration or compensation
- FOR 157 ...Having mathematical operation on initial measurement data (364/571.02)
- FOR 158 ....Including environmental factors (e.g., temperature) (364/571.03)
- FOR 159 ....Including predetermined stored data (364/571.04)
- FOR 160 ....Using difference involving initial measurement data (364/571.05)
- FOR 161 ....Using analog calculating elements (364/571.06)
- FOR 162 ...By table look-up (364/571.07)
- FOR 163 ...Using operator provided data (364/571.08)
- FOR 164 ..Filtering (364/572)
- FOR 165 ..Linearization (364/573)
- FOR 166 ..Noise reduction (364/574)
- FOR 167 ..Averaging (364/575)
- FOR 168 ..Fourier analysis (364/576)
- FOR 169 ..Interpolation/extrapolation (364/577)
- FOR 170 ..With control of testing or measuring apparatus (364/579)
- FOR 171 ..Programmed testing conditions (364/580)
- FOR 172 ..Weighting (364/581)
- FOR 173 ..Normalization (364/582)